

Search Notes

Application/Control No.

10/790,297

Examiner

John A. Tweel, Jr.

Applicant(s)/Patent under
Reexamination

SIWA ET AL.

Art Unit

2636

SEARCHED

Class	Subclass	Date	Examiner
340	457.4	9/1/2005	JAT
	438	9/1/2005	JAT
	439	9/1/2005	JAT
701	30	9/1/2005	JAT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner